## **Power MOSFET**

# 40 V, 3.8 m $\Omega$ , 85 A, Single N-Channel

#### **Features**

- Small Footprint (3.3 x 3.3 mm) for Compact Design
- Low R<sub>DS(on)</sub> to Minimize Conduction Losses
- Low Q<sub>G</sub> and Capacitance to Minimize Driver Losses
- These Devices are Pb–Free, Halogen Free/BFR Free and are RoHS Compliant

## **MAXIMUM RATINGS** (T<sub>J</sub> = 25°C unless otherwise noted)

Parar	Symbol	Value	Unit		
Drain-to-Source Voltag	$V_{DSS}$	40	V		
Gate-to-Source Voltage	Э		$V_{GS}$	±20	V
Continuous Drain		T <sub>C</sub> = 25°C	I <sub>D</sub>	85	Α
Current R <sub>θJC</sub> (Notes 1, 3)	Steady	T <sub>C</sub> = 100°C		60	
Power Dissipation	State	T <sub>C</sub> = 25°C	P <sub>D</sub>	55	W
R <sub>θJC</sub> (Note 1)		T <sub>C</sub> = 100°C		27	
Continuous Drain		$T_A = 25^{\circ}C$ $I_D$		20	Α
Current R <sub>0JA</sub> (Notes 1, 2, 3)	Steady	T <sub>A</sub> = 100°C		14	
Power Dissipation	State	T <sub>A</sub> = 25°C	$P_{D}$	3.2	W
R <sub>θJA</sub> (Notes 1 & 2)		T <sub>A</sub> = 100°C		1.6	
Pulsed Drain Current	Pulsed Drain Current $T_A = 25^{\circ}C$ , $t_p = 10 \mu s$			520	Α
Operating Junction and Storage Temperature			T <sub>J</sub> , T <sub>stg</sub>	-55 to +175	°C
Source Current (Body Diode)			I <sub>S</sub>	61	Α
Single Pulse Drain-to-Source Avalanche Energy (I <sub>L(pk)</sub> = 5 A)			E <sub>AS</sub>	202	mJ
Lead Temperature for Soldering Purposes (1/8" from case for 10 s)			TL	260	°C

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

#### THERMAL RESISTANCE MAXIMUM RATINGS

Parameter	Symbol	Value	Unit
Junction-to-Case - Steady State	$R_{\theta JC}$	2.7	°C/W
Junction-to-Ambient - Steady State (Note 2)	$R_{\theta JA}$	47	

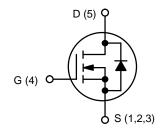
- The entire application environment impacts the thermal resistance values shown, they are not constants and are only valid for the particular conditions noted.
- 2. Surface-mounted on FR4 board using a 650 mm<sup>2</sup>, 2 oz. Cu pad.
- 3. Maximum current for pulses as long as 1 second is higher but is dependent on pulse duration and duty cycle.



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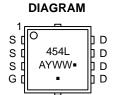
V <sub>(BR)DSS</sub>	R <sub>DS(ON)</sub> MAX	I <sub>D</sub> MAX		
40 V	$3.8~\text{m}\Omega$ @ $10~\text{V}$	0F		
40 V	6 mΩ @ 4.5 V	85 A		



**N-CHANNEL MOSFET** 



## WDFN8 (μ8FL) CASE 511AB



**MARKING** 

454L = Specific Device Code A = Assembly Location

Y = Year WW = Work Week ■ = Pb-Free Package

(Note: Microdot may be in either location)

#### ORDERING INFORMATION

See detailed ordering, marking and shipping information on page 5 of this data sheet.

## **ELECTRICAL CHARACTERISTICS** (T<sub>J</sub> = 25°C unless otherwise specified)

Parameter	Symbol	Test Condition		Min	Тур	Max	Unit
OFF CHARACTERISTICS							
Drain-to-Source Breakdown Voltage	V <sub>(BR)DSS</sub>	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$		40			V
Drain-to-Source Breakdown Voltage Temperature Coefficient	V <sub>(BR)DSS</sub> /				22		mV/°C
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	$V_{DSS}$ $V_{GS} = 0 \text{ V},$ $V_{DS} = 40 \text{ V}$ $T_{J} = 25 \degree$ $T_{J} = 125 \degree$				10	
						250	μΑ
Gate-to-Source Leakage Current	I <sub>GSS</sub>	$V_{DS} = 0 \text{ V}, V_{GS}$	<sub>S</sub> = 20 V			100	nA
ON CHARACTERISTICS (Note 4)							
Gate Threshold Voltage	V <sub>GS(TH)</sub>	$V_{GS} = V_{DS}, I_{D}$	= 50 μΑ	1.2	1.7	2.0	V
Threshold Temperature Coefficient	V <sub>GS(TH)</sub> /T <sub>J</sub>				-5.1		mV/°C
Drain-to-Source On Resistance	R <sub>DS(on)</sub>	V <sub>GS</sub> = 10 V	I <sub>D</sub> = 20 A		3.2	3.8	
		V <sub>GS</sub> = 4.5 V	I <sub>D</sub> = 20 A		4.8	6	mΩ
Forward Transconductance	9 <sub>FS</sub>	V <sub>DS</sub> = 15 V, I <sub>I</sub>	o = 40 A		80		S
Gate Resistance	$R_{G}$				1.4		Ω
CHARGES AND CAPACITANCES	•					•	
Input Capacitance	C <sub>ISS</sub>				1600		
Output Capacitance	Coss	V <sub>GS</sub> = 0 V, f = 1 MH	z, V <sub>DS</sub> = 25 V		590		pF
Reverse Transfer Capacitance	C <sub>RSS</sub>				21		1
Output Charge	Q <sub>OSS</sub>	V <sub>GS</sub> = 0 V, V <sub>DD</sub> = 20 V			21		nC
Total Gate Charge	Q <sub>G(TOT)</sub>	V <sub>GS</sub> = 10 V, V <sub>DS</sub> = 2	20 V; I <sub>D</sub> = 40 A		18		
Total Gate Charge	Q <sub>G(TOT)</sub>				8.2		1
Threshold Gate Charge	Q <sub>G(TH)</sub>				2		nC
Gate-to-Source Charge	$Q_GS$	$V_{GS} = 4.5 \text{ V}, V_{DS} = 3.5 \text{ V}$	20 V; I <sub>D</sub> = 40 A		3.8		
Gate-to-Drain Charge	$Q_GD$				2.1		1
Plateau Voltage	$V_{GP}$				3.2		V
SWITCHING CHARACTERISTICS (Note 5	5)						
Turn-On Delay Time	t <sub>d(ON)</sub>				9.3		
Rise Time	t <sub>r</sub>	$V_{GS} = 4.5 \text{ V}, V_{DS} = 20 \text{ V},$ $I_{D} = 40 \text{ A}, R_{G} = 2.5 \Omega$			100		ns
Turn-Off Delay Time	t <sub>d(OFF)</sub>				17		
Fall Time	t <sub>f</sub>				4		
DRAIN-SOURCE DIODE CHARACTERIS	TICS						
Forward Diode Voltage	ward Diode Voltage V <sub>SD</sub> V <sub>GS</sub> = 0 V.		T <sub>J</sub> = 25°C		0.86	1.2	.,
		$V_{GS} = 0 \text{ V},$ $I_{S} = 40 \text{ A}$	T <sub>J</sub> = 125°C		0.75		V
Reverse Recovery Time	t <sub>RR</sub>	$V_{GS} = 0 \text{ V, } dI_S/dt = 100 \text{ A/}\mu\text{s,}$ $I_S = 40 \text{ A}$			29		
Charge Time	t <sub>a</sub>				14		ns
Discharge Time	t <sub>b</sub>				15		1
Reverse Recovery Charge	$Q_{RR}$				20		nC

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

4. Pulse Test: pulse width  $\leq 300~\mu s$ , duty cycle  $\leq 2\%$ .

5. Switching characteristics are independent of operating junction temperatures.

#### TYPICAL CHARACTERISTICS

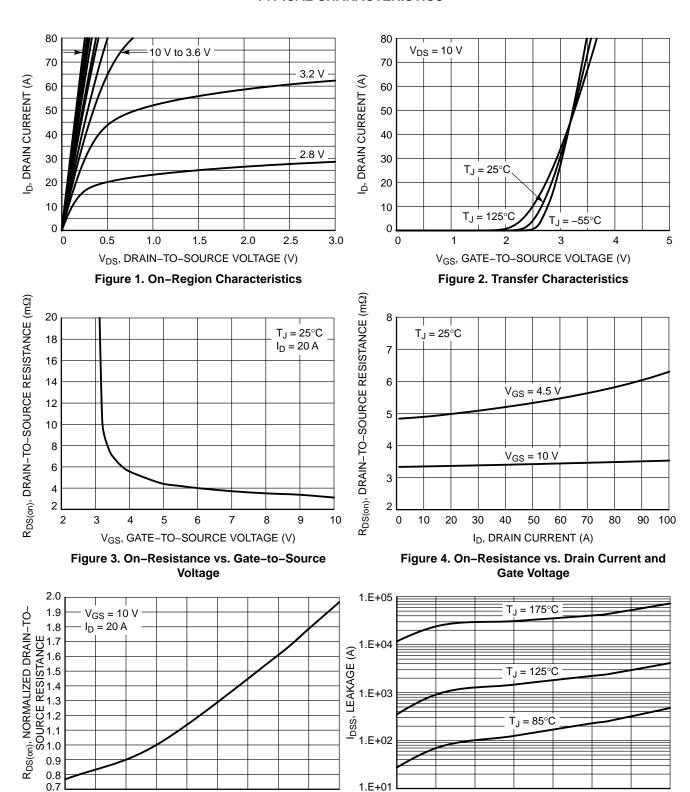


Figure 5. On–Resistance Variation with Temperature

TJ, JUNCTION TEMPERATURE (°C)

75

100

150

175

50

-50

-25

Figure 6. Drain-to-Source Leakage Current vs. Voltage

V<sub>DS</sub>, DRAIN-TO-SOURCE VOLTAGE (V)

35

40

20

15

#### **TYPICAL CHARACTERISTICS**

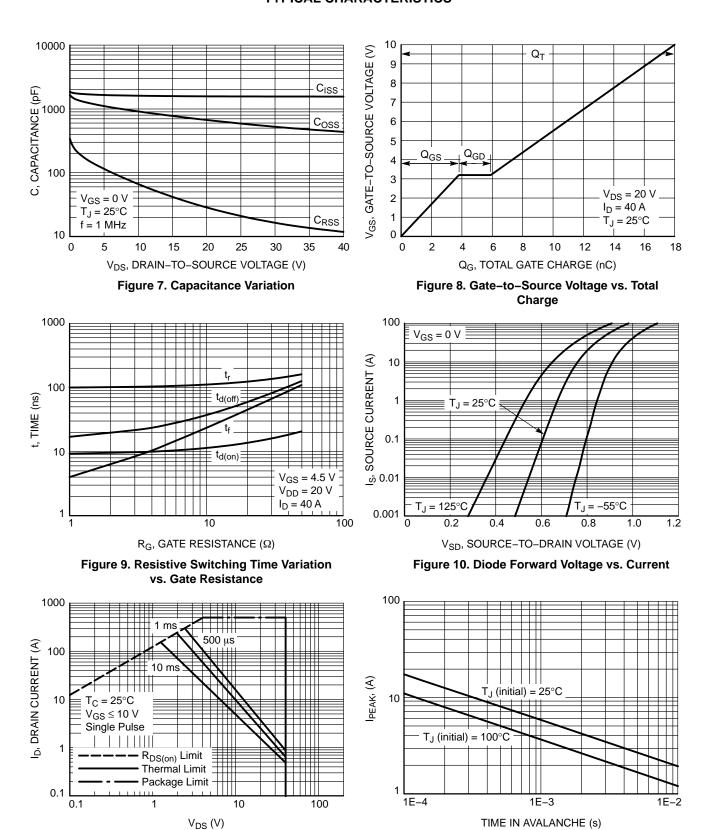


Figure 11. Safe Operating Area Figure 12. I<sub>PEAK</sub> vs. Time in Avalanche

#### TYPICAL CHARACTERISTICS

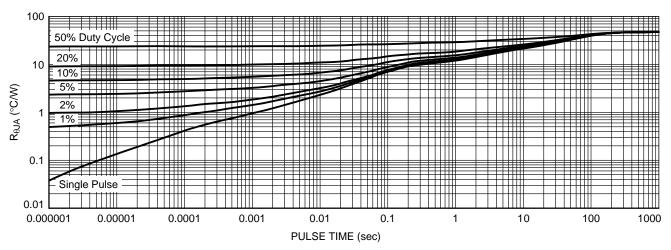


Figure 13. Thermal Characteristics

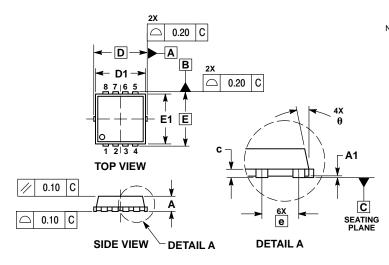
## **DEVICE ORDERING INFORMATION**

Device	Marking	Package	Shipping <sup>†</sup>
NTTFS5C454NLTAG	454L	WDFN8 (Pb–Free)	1500 / Tape & Reel
NTTFS5C454NLTWG	454L	WDFN8 (Pb–Free)	5000 / Tape & Reel

<sup>†</sup>For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.

#### PACKAGE DIMENSIONS

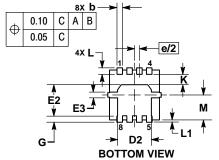
#### WDFN8 3.3x3.3, 0.65P CASE 511AB ISSUE D



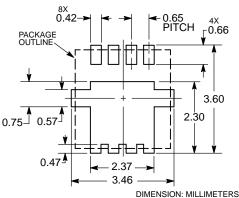
#### NOTES

- DIMENSIONING AND TOLERANCING PER ASME Y14.5M, 1994.
   CONTROLLING DIMENSION: MILLIMETERS.
- DIMENSION D1 AND E1 DO NOT INCLUDE MOLD FLASH PROTRUSIONS OR GATE BURRS.

	MILLIMETERS			INCHES			
DIM	MIN	NOM	MAX	MIN	NOM	MAX	
Α	0.70	0.75	0.80	0.028	0.030	0.031	
A1	0.00		0.05	0.000		0.002	
b	0.23	0.30	0.40	0.009	0.012	0.016	
С	0.15	0.20	0.25	0.006	0.008	0.010	
D	;	3.30 BSC		0.130 BSC			
D1	2.95	3.05	3.15	0.116	0.120	0.124	
D2	1.98	2.11	2.24	0.078	0.083	0.088	
E	3.30 BSC			0	.130 BSC	;	
E1	2.95	3.05	3.15	0.116	0.120	0.124	
E2	1.47	1.60	1.73	0.058	0.063	0.068	
E3	0.23	0.30	0.40	0.009	0.012	0.016	
е	0.65 BSC			0.026 BSC			
G	0.30	0.41	0.51	0.012	0.016	0.020	
K	0.65	0.80	0.95	0.026	0.032	0.037	
L	0.30	0.43	0.56	0.012	0.017	0.022	
L1	0.06	0.13	0.20	0.002	0.005	0.008	
M	1.40	1.50	1.60	0.055	0.059	0.063	
θ	0 °		12 °	0 °		12 °	



#### **SOLDERING FOOTPRINT\***



\*For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

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